

Notice of References Cited	Application/Control No. 10/541,897	Applicant(s)/Patent Under Reexamination LEE ET AL.
	Examiner Lauren Nguyen	Art Unit 2871

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0063234	04-2003	Oda et al.	349/65
*	B	US-6,339,458	01-2002	Ohkawa, Shingo	349/65
*	C	US-6,104,455	08-2000	Kashima, Keiji	349/65
*	D	US-2001/0035928	11-2001	Kuroiwa et al.	349/115
*	E	US-6,369,945	04-2002	Sakuramoto et al.	359/494
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	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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